

Some propositions about the use of Ornstein-Uhlenbeck process for degradation modeling and RUL estimation

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Introduction & Outline

Context & Motivations

Introduction & Outline

Time dependent
Ornstein-Uhlenbeck
Process

Maximum Likelihood
Estimation

Residual Useful Lifetime
Linear diffusion and
Time dependent O.-U.
Comparison

Conclusion

☒ Context:

- Management of deteriorating systems or components
- Gradually deteriorating systems or devices
- Degradation records at (random) discrete inspection times
- Failure time = first passage time

☒ **Motivation:** built a stochastic process for degradation modeling under the assumption that information is given about mean and variance of the degradation evolution

- ➔ Lifetime prognostic (Remaining Useful Lifetime)
- ➔ Extend the list of stochastic processes that can help for maintenance decision making and optimisation

Outline

- ☒ Time dependent Ornstein-Uhlenbeck Process
- ☒ Parametric Estimation
- ☒ Remaining Useful Lifetime Estimation
- ☒ Wiener with drift vs time dependent O.-U.
- ☒ Conclusion



Time dependent Ornstein-Uhlenbeck Process



Ornstein-Uhlenbeck Process

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☒ **Definition:** Stochastic Process solution of the SDE

$$X_t = X_0 + \int_0^t \lambda(\mu - X_u) du + \int_0^t \sigma dB_u$$

where $\mu, \lambda > 0$ and $\sigma > 0$ are parameters and B_t is the standard Brownian motion.

☒ **Explicit solution**

$$X_t = x_0 e^{-\lambda t} + \mu(1 - e^{-\lambda t}) + \sigma \int_0^t e^{-\lambda(t-s)} dB_s$$

☒ **Stationary, Gaussian and Markovian process.**

☒ **Mean reverting property:** over time, X_t tends to drift toward its long-term mean.

Time dependent O.-U. Process

- ☒ Choice of Stochastic Differential Equation to built a stochastic process with given mean and variance

➡ “Ornstein-Uhlenbeck like” SDE - non-homogeneous in time

$$X_t = X_0 + \int_0^t (a(s)X_s + b(s)) ds + \int_0^t \sigma(s) dB_s$$

➡ Explicit form of X_t

$$X_t = \Phi_0(t) \left[X_0 + \int_0^t \frac{b(s)}{\Phi_0(s)} ds + \int_0^t \frac{\sigma(s)}{\Phi_0(s)} dB_s \right]$$

where

$$\Phi_u(t) \triangleq \exp \left(\int_u^t a(s) ds \right) \quad (u \leq t)$$

(Hypothesis on a and σ e.g. as $\int_0^{+\infty} a(u) du = -\infty$, $\int_0^{+\infty} \left(\frac{\sigma(u)}{\Phi_0(u)} \right)^2 du = +\infty$)

Time dependent O.-U. Process

☒ From explicit expression of X_t or from Chapman-Kolmogorov equations:

- Mean

$$\mathbb{E}[X_t] = \Phi_0(t) \left(\mathbb{E}[X_0] + \int_0^t \frac{b(s)}{\Phi_0(s)} ds \right)$$

- Covariance

$$\text{cov}(X_t, X_s) = \Phi_0(t)\Phi_0(s) \left\{ \text{var}[X_0] + \int_0^{t \wedge s} \left(\frac{\sigma(s)}{\Phi_0(s)} \right)^2 ds \right\}$$

- Variance

$$\text{var}[X_t] = \Phi_0^2(t) \left\{ \text{var}[X_0] + \left(\int_0^t \left(\frac{\sigma(s)}{\Phi_0(s)} \right)^2 ds \right) \right\}$$

Time dependent O.-U. Process

- ☒ Hypothesis: $\sigma(t) = \sigma$ is a constant
- ☒ Choice of $a(t)$, $b(t)$ and σ such that:

$$\mathbb{E}[X_t] = m(t) \text{ and } \text{var}[X_t] = v(t)$$

where m and v are chosen (parametric) continuously differentiable functions, $\sigma > 0$ and $\forall t > 0, v(t) > 0$ and $\sigma^2 > v'(t)$.

$$\Leftrightarrow a(t) = \frac{v'(t) - \sigma^2}{2v(t)} \text{ and } b(t) = m'(t) - a(t)m(t)$$

$$X_t = X_0 + \int_0^t \left\{ \left(\frac{v'(s) - \sigma^2}{2v(s)} \right) X_s + m'(s) - m(s) \left(\frac{v'(s) - \sigma^2}{2v(s)} \right) \right\} ds + \sigma \int_0^t dB_s$$

Time dependent O.-U. Process

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$$\Leftrightarrow a(t) = \frac{v'(t) - \sigma^2}{2v(t)} \text{ and } b(t) = m'(t) - a(t)m(t)$$

$$X_t = e^{-\alpha(t,0)} \left(X_0 - \beta(t,0) + \int_0^t \sigma e^{\alpha(u,s)} dB_u \right)$$

$$\text{with } \alpha(t,s) = - \int_s^t a(u) du \text{ and } \beta(t,s) = m(s) - m(t) e^{\alpha(t,s)}$$

Properties & Particular cases

- ☒ Mean Reverting property : long-term prognosis not influenced by last observation

$$\mathbb{E}[X_t | X_s = y] = m(t) + (y - m(s)) \exp\left(\int_s^t \frac{v'(u) - \sigma^2}{2v(u)} du\right)$$

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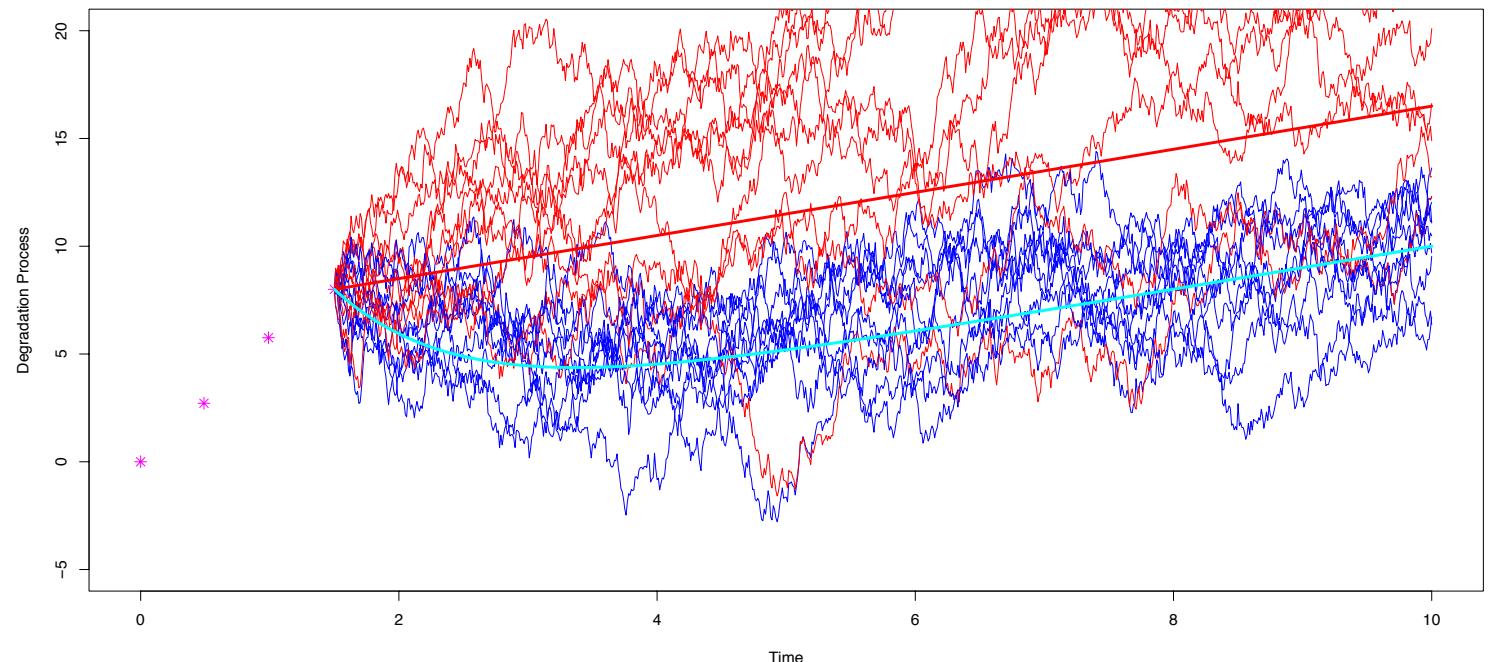


Fig.1 : Brownian and O.-U. processes with identical mean function starting from the origin

Properties & Particular cases

- ☒ Mean Reverting property : long-term prognosis not influenced by last observation

$$\mathbb{E}[X_t | X_s = y] = m(t) + (y - m(s)) \exp\left(\int_s^t \frac{\nu'(u) - \sigma^2}{2\nu(u)} du\right)$$

☒ Remarks

- If $\nu(t) = \sigma^2 t$ (i.e. $a(t) = 0$) then $X_t = m(t) + \sigma B_t$
- If $\nu(t) = \nu$ constant then $a(t)$ constant and $\nu = -\frac{\sigma^2}{2a}$

More generally if $a(t)$ is a constant (< 0) then

$$\nu(t) = (\nu(0) + \frac{\sigma^2}{2a}) e^{2at} - \frac{\sigma^2}{2a} \xrightarrow{t \rightarrow +\infty} -\frac{\sigma^2}{2a}$$

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Maximum Likelihood Estimation

Estimation (MLE)

- ☒ Density function of X_t , with $p(x, t|y, s) = \mathcal{L}(X_t|X_s = y)$:

$$p(x, t|x_s, s) = \frac{e^{\alpha(t,s)}}{\sqrt{4\pi\gamma(t,s)}} \exp\left(-\frac{(xe^{\alpha(t,s)} + \beta(t, s) - y)^2}{4\gamma(t, s)}\right)$$

where $\alpha(t, s) = -\ln(\phi_s(t))$, $\beta(t, s) = m(s) - \frac{m(t)}{\phi_s(t)}$ and $\gamma(t, s) = \int_s^t \frac{\sigma^2}{2\phi_s^2(u)} du$.

- ☒ Proof (different possible ways):
 - As a solution of the Fokker-Planck equation

$$\frac{\partial p(x, t)}{\partial t} = -\frac{\partial}{\partial x} \left(a(t)x + m'(t) - a(t)m(t) \right) p(x, t) + \frac{\sigma^2}{2} \frac{\partial^2}{\partial x^2} p(x, t)$$

Estimation (MLE)

- ☒ Density function of X_t , with $p(x, t|y, s) = \mathcal{L}(X_t|X_s = y)$:

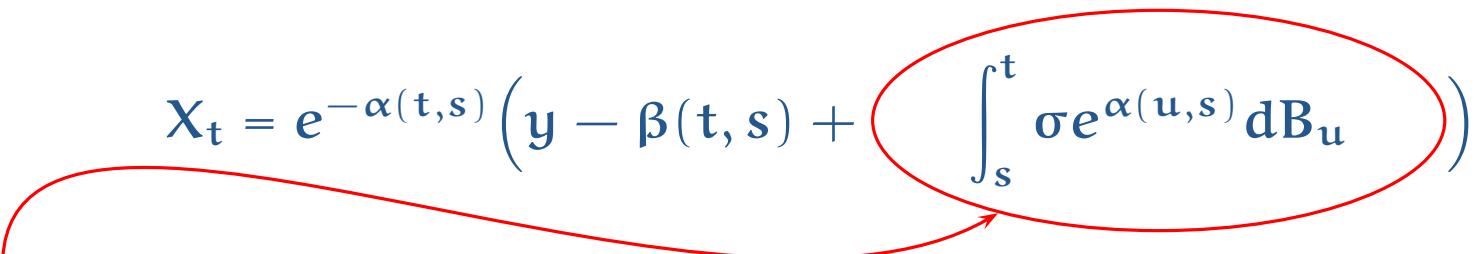
$$p(x, t|x_s, s) = \frac{e^{\alpha(t,s)}}{\sqrt{4\pi\gamma(t,s)}} \exp\left(-\frac{(xe^{\alpha(t,s)} + \beta(t,s) - y)^2}{4\gamma(t,s)}\right)$$

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- ☒ Proof (different possible ways):

- From the explicit expression of X_t starting from y at time s

$$X_t = e^{-\alpha(t,s)} \left(y - \beta(t,s) + \int_s^t \sigma e^{\alpha(u,s)} dB_u \right)$$



Z_t ($t \geq s$) zero mean Gaussian process $\sim \mathcal{N}(0, 2\gamma(t, s))$

Estimation (MLE)

☒ Data set: n components.

For component i , m_i records - $\{(t_{i,j}, x_{i,j}), j = 1, \dots, m_i\}$

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☒ Log-likelihood:

$$\log L(\theta) = \sum_{i=1}^n \sum_{j=0}^{m_i-1} \log(p_\theta(x_{i,j+1}, t_{i,j+1} | x_{i,j}, t_{i,j}))$$

☒ Parameters: choice of parametric expressions of $m(t)$ and $v(t)$ depending on the data set

e.g. $m(t) = \lambda((t + 1)^\mu - 1) + m_0$ and $v(t) = -\frac{\sigma^2}{2a}(1 - \exp(2at))$

⇒ $\theta = (\lambda, \mu, a, \sigma, m_0)$

Numerical results

- ☒ Log-likelihood maximization with classical numerical algorithm (Nelder-Mead)
- ☒ Illustration on partial data proposed by EDF for AMMSI

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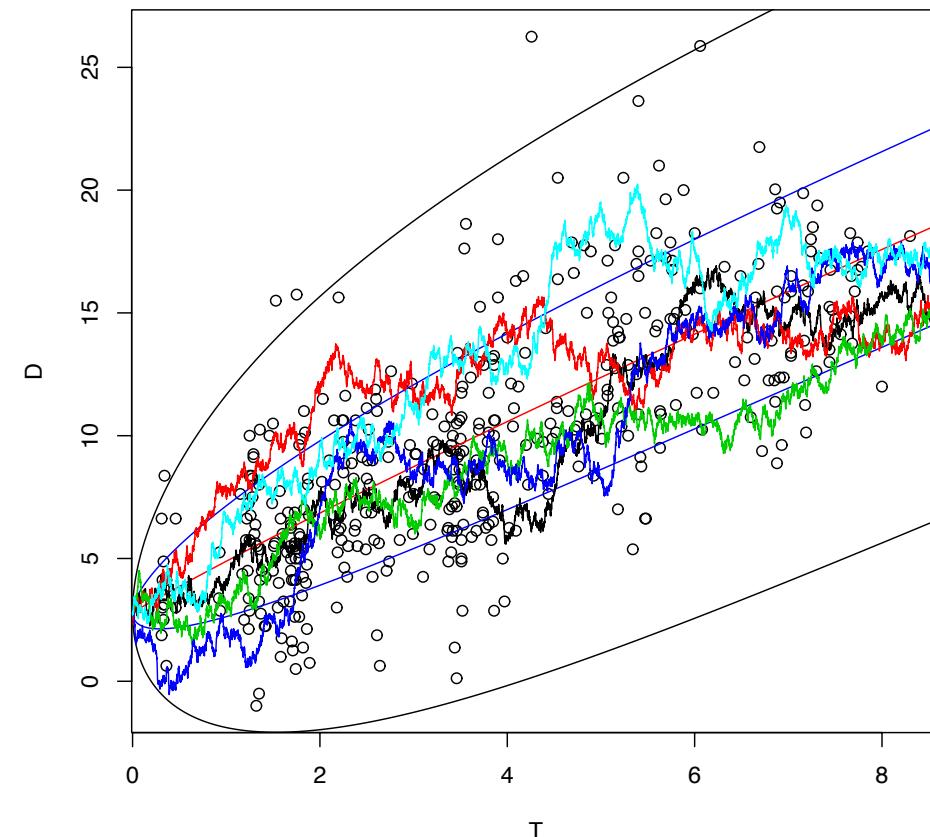
$$\lambda = 2.44$$

$$\mu = 0.89$$

$$\sigma = 2.46$$

$$a = -0.18$$

$$m_0 = 2.8$$



Residual Useful Lifetime

Residual Useful Lifetime

- $RUL_s = \inf\{t \geq s, X_t \notin \mathcal{U}\} - s$ where \mathcal{U} = useful domain
 - ➡ case of a constant failure limit: system failure as the degradation level reaches a given value $\mathcal{U} = \{x ; x < L\}$
- First passage problem = first hitting time of the failure level L based on the degradation level at last inspection time
 - ➡ Quantity of interest:

$$g(u|y, s) = \mathcal{L}(RUL_s | X_s = y)(u)$$

- Numerical expression of $g(u|y, s)$ as the solution of a non-singular Volterra integral equation

$$g(t|y, s) = -2K(L, t|y, s) + 2 \int_s^t g(u|y, s) K(L, t|L, u) du.$$

Voltera integral equation

- ☒ Result established for Gauss-Markov process¹ (see *Buonocore et al.(1987)*)

$$Y_t = \eta(t) + h_2(t)B_{h_1(t)/h_2(t)}$$

- ➡ expression of the kernel as:

$$\begin{aligned} K(L, t|y, s) &= \left\{ -\frac{\eta'(t)}{2} - \frac{L - \eta(t)}{2} \frac{h'_1(t)h_2(s) - h'_2(t)h_1(s)}{h_1(t)h_2(s) - h_2(t)h_1(s)} \right. \\ &\quad \left. - \frac{y - \eta(s)}{2} \frac{h'_2(t)h_1(t) - h_2(t)h'_1(t)}{h_1(t)h_2(s) - h_2(t)h_1(s)} \right\} p(L, t|y, s) \end{aligned}$$

- ☒ Time dependent O.-U. process can be written as

$$X_t = (y - \beta(t, s))e^{-\alpha(t, s)} + e^{-\alpha(t, s)}B_{2\gamma(t, s)}$$

- ➡ Kernel expression by taking $\eta(t) = (y - \beta(t, s))e^{-\alpha(t, s)}$, $h_1(t) = 2e^{-\alpha(t, s)}\gamma(t, s)$ and $h_2(t) = e^{-\alpha(t, s)}$ for $t \geq s$.

¹ B_* standard Brownian motion

First passage time

☒ Trapezoid numerical scheme:

$$g_1 = -2K(L(t_0 + h), t_0 + h | x_0, t_0)$$

$$g_k = -2K(L(t_0 + kh), t_0 + kh | x_0, t_0)$$

$$+ 2h \sum_{j=1}^{k-1} g_j K(L(t_0 + kh), t_0 + kh | L(t_0 + jh), t_0 + jh)$$

$$k = 2, 3, \dots$$

☒ CDF of the first passage time ($t = 0, y = 0$)

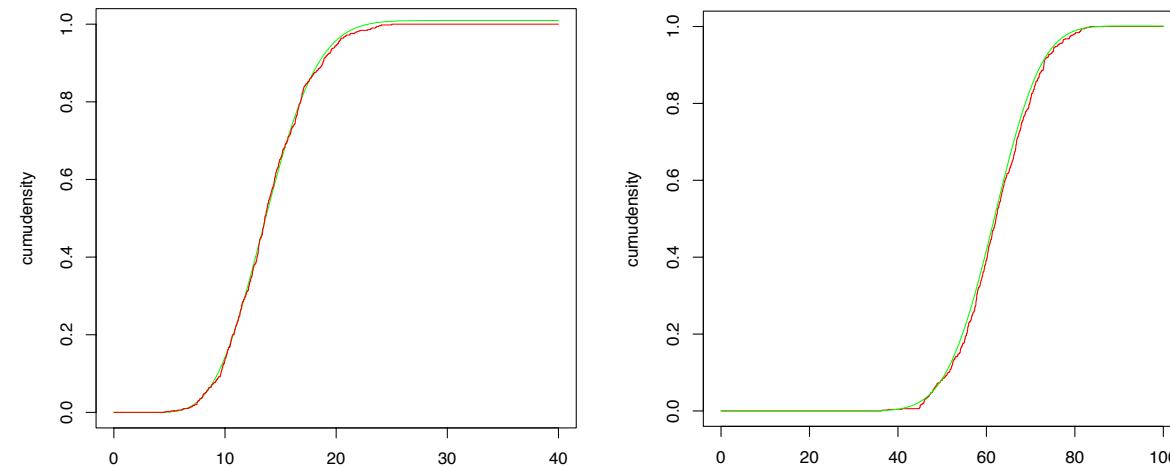


Fig2: cdf - Volterra (green) and Monte Carlo (red) for $L = 25$ (left) and $L = 50$ (right)

Linear diffusion and Time dependent O.-U. Comparison

Framework for comparison

- ☒ Data set: 415 records of degradation, 159 independent equipments
- ☒ Two possible processes with mean $m(t) = \lambda((t - 1)^\mu - 1) + m_0$
($X_0 = m_0$ and $v_0 = 0$ given)
- Linear diffusion process: 4 parameters ($\lambda, \mu, m_0, \sigma$)

$$X_t^{\text{BM}} = m(t) + \sigma B_t$$

- Time dependent O.-U. process: 5 parameters ($\lambda, \mu, m_0, \sigma, a$)

$$X_t^{\text{OU}} = \int_0^t \left(a(X_s - m(s)) + m'(s) \right) ds + \int_0^t \sigma dB_s$$

- ☒ Maximum likelihood estimation

parameters	BM	OU
λ	1.8735	2.4403
μ	1.0059	0.8892
σ	2.1529	2.4641
a	–	-0.1807
m_0	2.9881	2.8075
variance	4.6352t	16.8033(1-exp(-0.3613t))

Exemples of trajectories

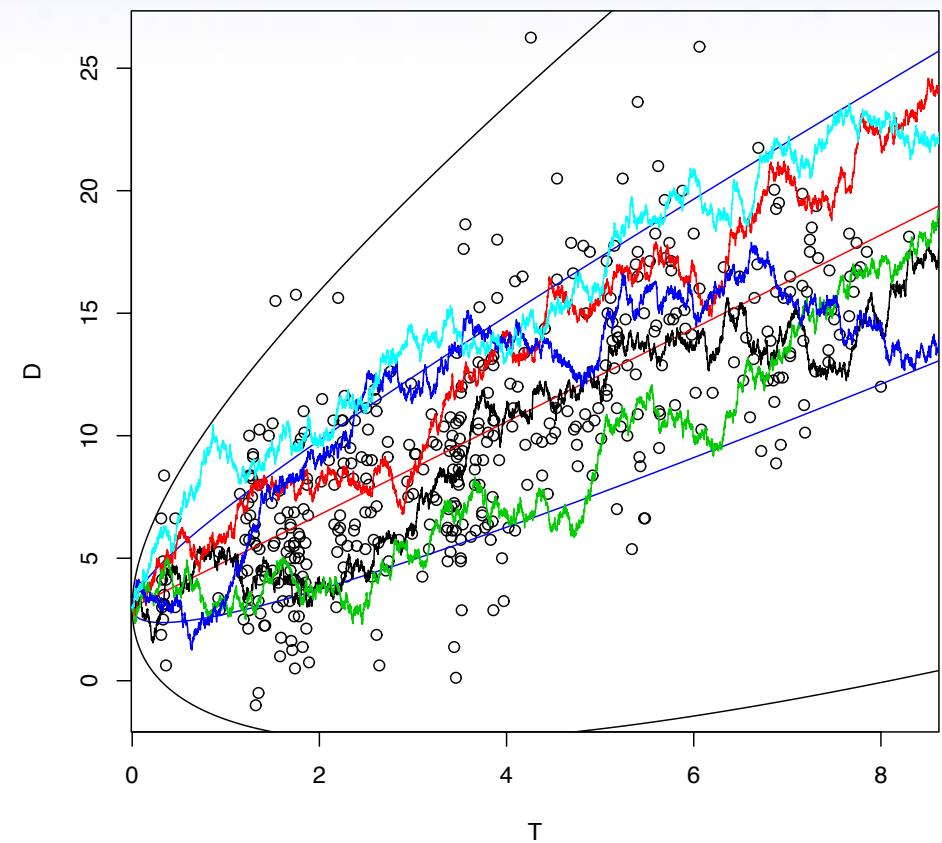
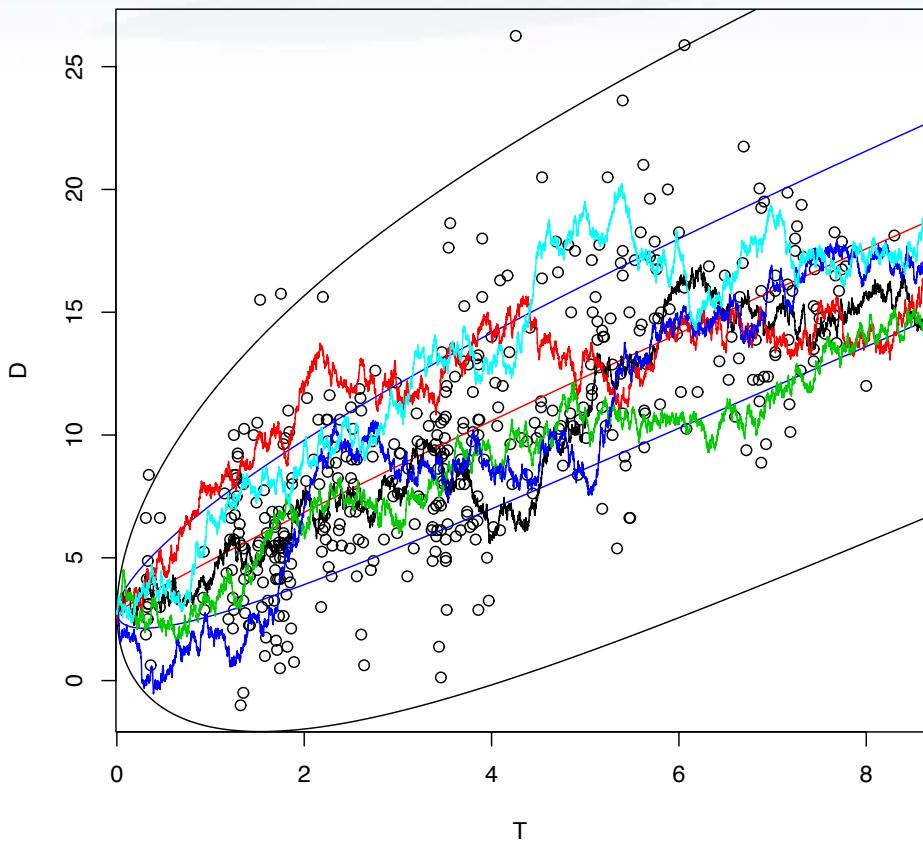


Fig.3: Exemple of trajectories for O.-U. process (left) and Brownian Motion (right)

Evaluation criterions and results

☒ Three criterions (heuristic - non i.d. random variables)

1. Akaïke Information Criterion $AIC = 2k - 2 \ln L(\theta^*)$

$$2. C_1 = \sum_{i=1}^n \sum_{j=0}^{m_i-1} P\left((X_{t_{i,(j+1)}} - x_{i,(j+1)}) \in [-\epsilon, \epsilon] | X_{t_{i,j}} = x_{i,j}\right)$$

$$3. C_2 = \sum_{i=1}^n \sum_{j=0}^{m_i-1} \sum_{k=j+1}^{m_i-1} P\left((X_{t_{i,k}} - x_{i,k}) \in [-\epsilon, \epsilon] | X_{t_{i,j}} = x_{i,j}\right)$$

☒ Fitting goodness results

criterion ²	BM	OU
AIC	2048.64	2021.044
C ₁	115.0321	119.3473
C ₂	193.2144	204.8864

²In the calculation of C_1 and C_2 , the tolerance level is $\epsilon = 0.25$ (step-size = 0.01 for numeric integration).

First passage probability laws

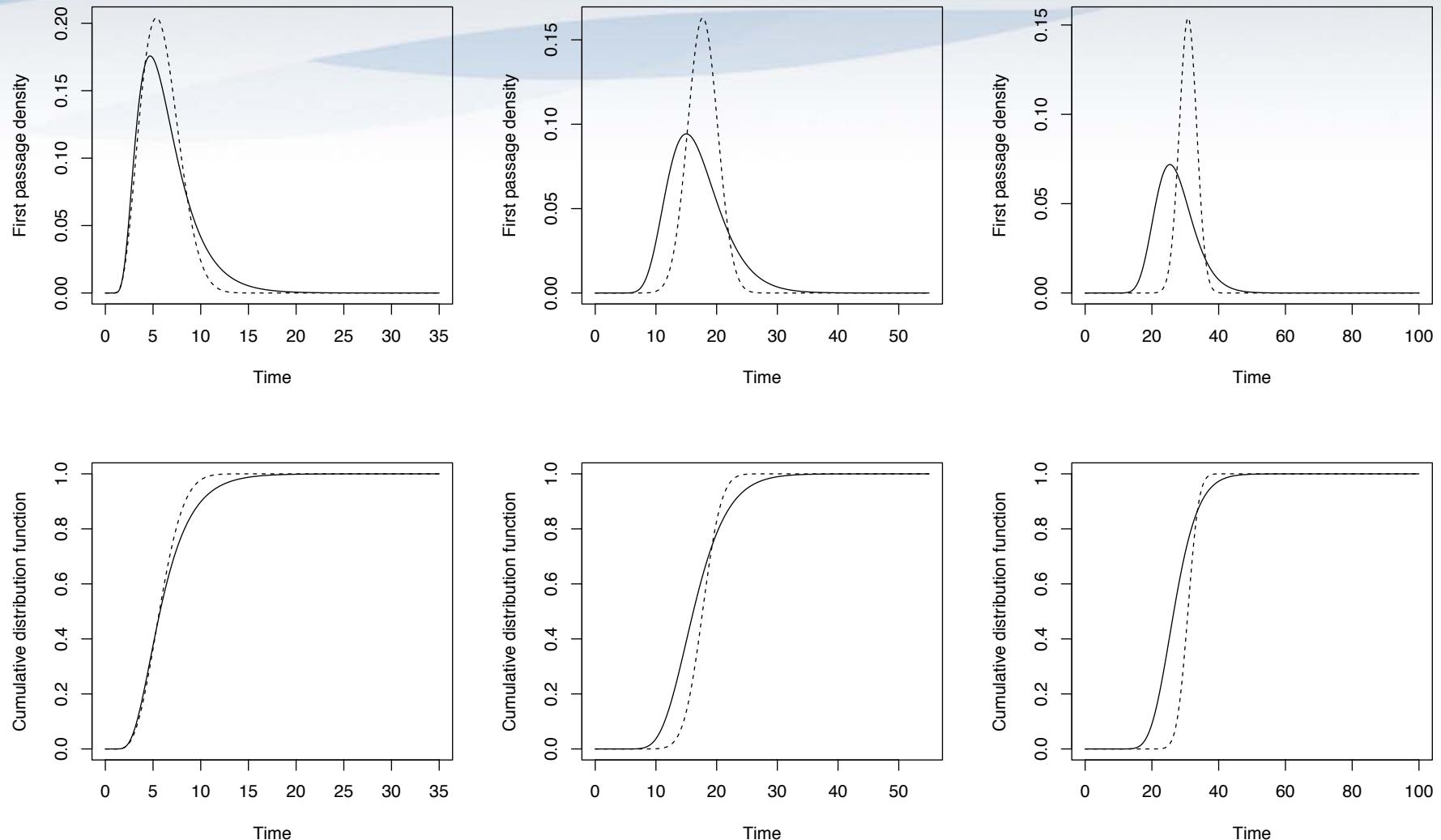


Fig.4: First passage pdf and cdf for $L = 15, 35$ and 55

obtained with O.-U. process (dashed) and Brownian Motion (solid)

Conclusion

Conclusion

- ☒ Construction of a stochastic process for degradation modeling
 - starting from Ornstein-Uhlenbeck process
 - possible way to take into account some specific mean or variance shapes

- ☒ Numerical feasibility study for numerical estimation
 - of the process parameters (parametric expression of mean and variance, constant diffusion coefficient)
 - of the Remaining Useful Lifetime

... and still work to do...